

# MC10137

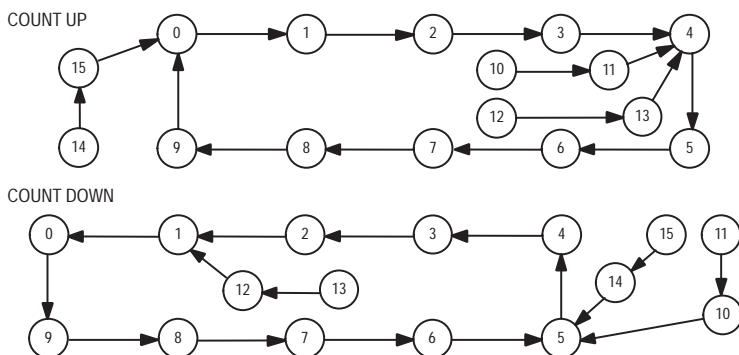
## Universal Decade Counter

The MC10137 is a high speed synchronous counter that can count up, down, preset, or stop count at frequencies exceeding 100 MHz. The flexibility of this device allows the designer to use one basic counter for most applications. The synchronous count feature makes the MC10137 suitable for either computers or instrumentation.

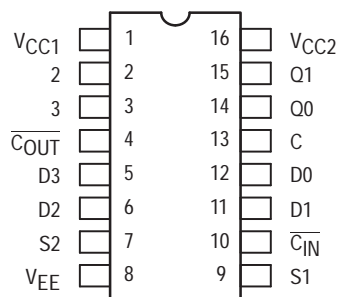
Three control lines (S1, S2, and Carry In) determine the operation mode of the counter. Lines S1 and S2 determine one of four operations; preset (program), increment (count up), decrement (count down), or hold (stop count). Note that in the preset mode a clock pulse is necessary to load the counter, and the information present on the data inputs (D0, D1, D2, and D3) will be entered into the counter. Carry Out goes low on the terminal count. The Carry Out on the MC10137 is partially decoded from Q1 and Q2 directly, so in the preset mode the condition of the Carry Out after the Clock's positive excursion will depend on the condition of Q1 and/or Q2. The counter changes state only on the positive going edge of the clock. Any other input may change at any time except during the positive transition of the clock. The sequence for counting out of improper states is as shown in the State Diagrams.

- $P_D = 625 \text{ mW typ/pkg (No Load)}$
- $f_{\text{count}} = 150 \text{ MHz typ}$
- $t_{pd} = 3.3 \text{ ns typ (C-Q)}$
- $= 7.0 \text{ ns typ (C-}\overline{\text{C}}_{\text{out}})$
- $= 5.0 \text{ ns typ (}\overline{\text{C}}_{\text{in}}\text{-}\overline{\text{C}}_{\text{out}})$

### STATE DIAGRAMS



### DIP PIN ASSIGNMENT



Pin assignment is for Dual-in-Line Package.

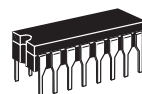
For PLCC pin assignment, see the Pin Conversion Tables on page 18 of the ON Semiconductor MECL Data Book (DL122/D).



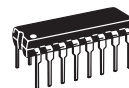
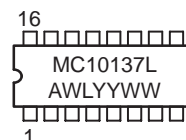
ON Semiconductor

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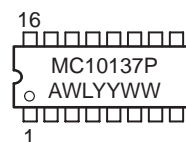
### MARKING DIAGRAMS



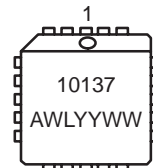
CDIP-16  
L SUFFIX  
CASE 620



PDIP-16  
P SUFFIX  
CASE 648



PLCC-20  
FN SUFFIX  
CASE 775



A = Assembly Location  
WL = Wafer Lot  
YY = Year  
WW = Work Week

### FUNCTION SELECT TABLE

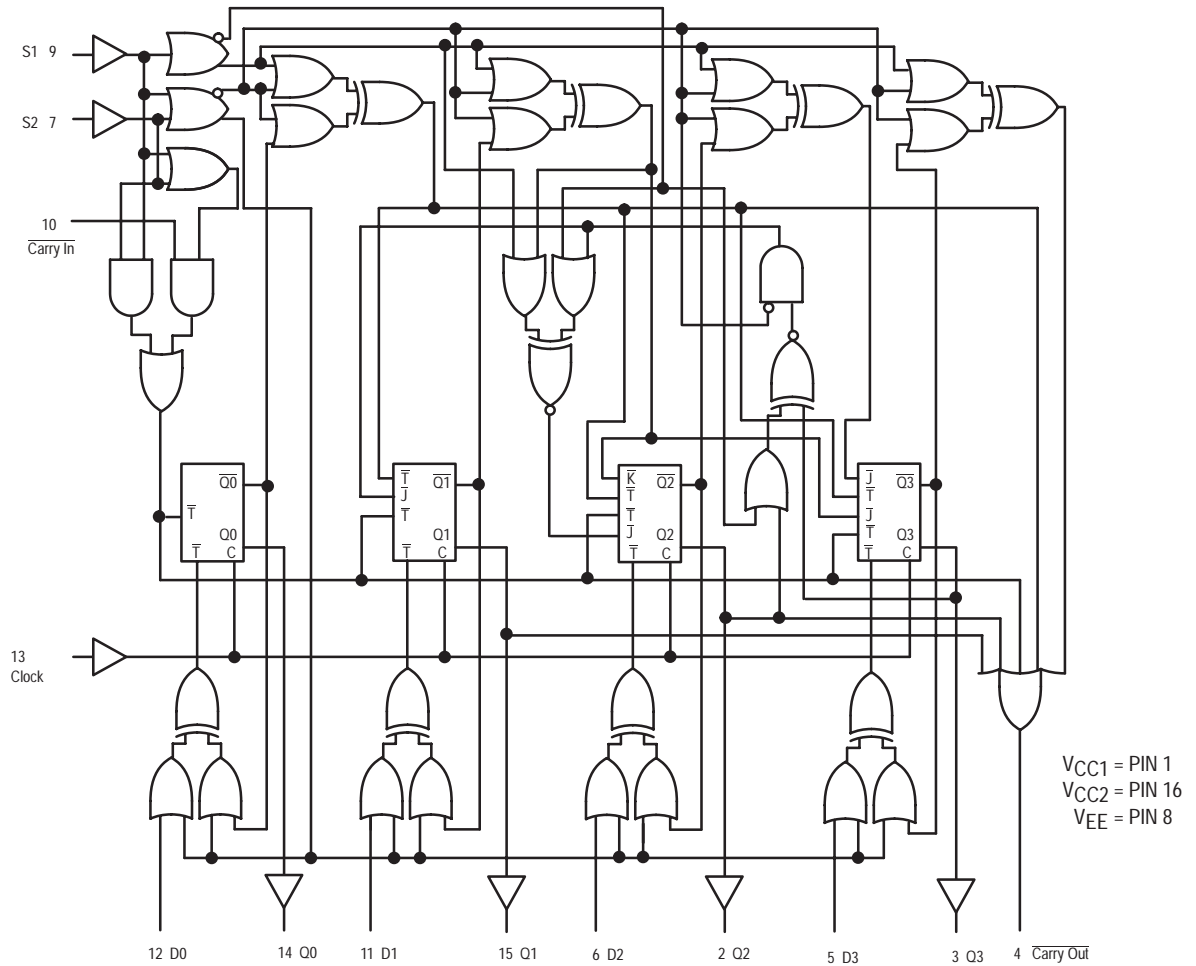
S1	S2	Operating Mode
L	L	Preset (Program)
L	H	Increment (Count Up)
H	L	Decrement (Count Down)
H	H	Hold (Stop Count)

### ORDERING INFORMATION

Device	Package	Shipping
MC10137L	CDIP-16	25 Units / Rail
MC10137P	PDIP-16	25 Units / Rail
MC10137FN	PLCC-20	46 Units / Rail

# MC10137

## LOGIC DIAGRAM



**NOTE:** Flip-flops will toggle when all  $\bar{T}$  inputs are low.

## SEQUENTIAL TRUTH TABLE\*

INPUTS								OUTPUTS				
S1	S2	D0	D1	D2	D3	$\overline{\text{Carry In}}$	Clock **	Q0	Q1	Q2	Q3	$\overline{\text{Carry Out}}$
L	L	H	H	H	L	X	H	H	H	H	L	H
L	H	X	X	X	X	L	H	L	L	L	H	H
L	H	X	X	X	X	L	H	H	L	L	H	L
L	H	X	X	X	X	L	H	L	L	L	L	H
L	H	X	X	X	X	L	H	H	L	L	L	H
L	H	X	X	X	X	H	L	H	L	L	L	H
L	H	X	X	X	X	H	H	H	L	L	L	H
L	H	X	X	X	X	X	H	H	L	L	L	H
L	L	H	H	L	L	X	H	H	H	L	L	H
H	L	X	X	X	X	L	H	L	H	L	L	H
H	L	X	X	X	X	L	H	H	L	L	L	H
H	L	X	X	X	X	L	H	L	L	L	L	L


\* Truth table shows logic states assuming inputs vary in sequence shown from top to bottom.

\*\* A clock H is defined as a clock input transition from a low to a high logic level.

## ELECTRICAL CHARACTERISTICS

Characteristic		Symbol	Pin Under Test	Test Limits						Unit	
				−30°C		+25°C			+85°C		
				Min	Max	Min	Typ	Max	Min		Max
Power Supply Drain Current		I <sub>E</sub>	8		165		120	150		165	mAdc
Input Current		I <sub>inH</sub>	5,6,11,12 7 9,10 13		350 425 390 460			220 265 245 290		220 265 245 290	μAdc
		I <sub>inL</sub>	All	0.5		0.5			0.3		μAdc
Output Voltage	Logic 1	V <sub>OH</sub>	14 (NO TAG)	−1.060	−0.890	−0.960		−0.810	−0.890	−0.700	Vdc
Output Voltage	Logic 0	V <sub>OL</sub>	14 (NO TAG)	−1.890	−1.675	−1.850		−1.650	−1.825	−1.615	Vdc
Threshold Voltage	Logic 1	V <sub>OHA</sub>	14 (NO TAG)	−1.080		−0.980			−0.910		Vdc
Threshold Voltage	Logic 0	V <sub>OLA</sub>	14 (NO TAG)		−1.655			−1.630		−1.595	Vdc
Switching Times (50Ω Load)											ns
Propagation Delay Clock Input		t <sub>13+14+</sub>	14	0.8	4.8	1.0	3.3	4.5	1.1	5.0	
		t <sub>13+14−</sub>	14	0.8	4.8	1.0	3.3	4.5	1.1	5.0	
		t <sub>13+4+</sub>	4	2.0	10.9	2.5	7.0	10.5	2.4	11.5	
		t <sub>13+4−</sub>	4	2.0	10.9	2.5	7.0	10.5	2.4	11.5	
$\overline{\text{Carry In}}$ to $\overline{\text{Carry Out}}$		t <sub>10−4−</sub>	4 (NO TAG)	1.6	7.4	1.6	5.0	6.9	1.9	7.5	
		t <sub>10+4+</sub>	4	1.6	7.4	1.6	5.0	6.9	1.9	7.5	
Setup Time	Data Inputs	t <sub>12+13+</sub>	14	3.5		3.5			3.5		
		t <sub>12−13+</sub>	14	3.5		3.5			3.5		
	Select Inputs	t <sub>9+13+</sub>	14	7.5		7.5			7.5		
		t <sub>7+13+</sub>	14	7.5		7.5			7.5		
	$\overline{\text{Carry In}}$ Input	t <sub>10−13+</sub>	14	4.5		3.7			4.5		
		t <sub>13+10+</sub>	14	−1.0		−1.0			−1.0		
Hold Time	Data Inputs	t <sub>13+12+</sub>	14	0		0			0		
		t <sub>13+12−</sub>	14	0		0			0		
	Select Inputs	t <sub>13+9+</sub>	14	−2.5		−2.5			−2.5		
		t <sub>13+7+</sub>	14	−2.5		−2.5			−2.5		
	$\overline{\text{Carry In}}$ Input	t <sub>13+10−</sub>	14	−1.6		−1.6			−1.6		
		t <sub>10+13+</sub>	14	4.0		3.1			4.0		
Counting Frequency		f <sub>countup</sub>	14	125		125	150		125		MHz
		f <sub>countdown</sub>	14	125		125	150		125		
Rise Time	(20 to 80%)	t <sub>4+</sub>	4	0.9	3.3	1.1	2.0	3.3	1.1	3.5	ns
		t <sub>14+</sub>	14	0.9	3.3	1.1	2.0	3.3	1.1	3.5	
Fall Time	(20 to 80%)	t <sub>4−</sub>	4	0.9	3.3	1.1	2.0	3.3	1.1	3.5	
		t <sub>14−</sub>	14	0.9	3.3	1.1	2.0	3.3	1.1	3.5	

1. Individually apply  $V_{ILmin}$  to pin under test.


2. Measure output after clock pulse   $V_{IH}$  appears at clock input (Pin 13).

3. Before test set Q1 and Q2 outputs to a logic low.

## ELECTRICAL CHARACTERISTICS (continued)

@ Test Temperature			TEST VOLTAGE VALUES (Volts)					(V <sub>CC</sub> ) Gnd
			V <sub>IHmax</sub>	V <sub>ILmin</sub>	V <sub>IHAmin</sub>	V <sub>ILAmx</sub>	V <sub>EE</sub>	
			–30°C	–0.890	–1.890	–1.205	–1.500	–5.2
			+25°C	–0.810	–1.850	–1.105	–1.475	–5.2
			+85°C	–0.700	–1.825	–1.035	–1.440	–5.2
Characteristic	Symbol	Pin Under Test	TEST VOLTAGE APPLIED TO PINS LISTED BELOW					(V <sub>CC</sub> ) Gnd
			V <sub>IHmax</sub>	V <sub>ILmin</sub>	V <sub>IHAmin</sub>	V <sub>ILAmx</sub>	V <sub>EE</sub>	
Power Supply Drain Current	I <sub>E</sub>	8					8	1, 16
Input Current	I <sub>inH</sub>	5,6,11,12	5,6,11,12				8	1, 16
		7	7				8	1, 16
		9,10	9,10				8	1, 16
		13	13				8	1, 16
	I <sub>inL</sub>	All		Note NO TAG			8	1, 16
Output Voltage Logic 1	V <sub>OH</sub>	14 (NO TAG)	12	7, 9			8	1, 16
Output Voltage Logic 0	V <sub>OL</sub>	14 (NO TAG)		7, 9			8	1, 16
Threshold Voltage Logic 1	V <sub>OHA</sub>	14 (NO TAG)		7, 9	12		8	1, 16
Threshold Voltage Logic 0	V <sub>OLA</sub>	14 (NO TAG)		7, 9		12	8	1, 16
Switching Times (50Ω Load)			+1.11V	+0.31V	Pulse In	Pulse Out	–3.2 V	+2.0 V
Propagation Delay Clock Input	t <sub>13+14+</sub>	14	12		13	14	8	1, 16
	t <sub>13+14–</sub>	14			13	14	8	1, 16
	t <sub>13+4+</sub>	4	7		13	4	8	1, 16
	t <sub>13+4–</sub>	4	7		13	4	8	1, 16
Carry In to Carry Out	t <sub>10–4–</sub>	4 (NO TAG)	7	13	10	4	8	1, 16
	t <sub>10+4+</sub>	4	7	13	10	4	8	1, 16
Setup Time Data Inputs	t <sub>12+13+</sub>	14		7, 9	12, 13	14	8	1, 16
	t <sub>12–13+</sub>	14		7, 9	12, 13	14	8	1, 16
Select Inputs	t <sub>9+13+</sub>	14			9, 13	14	8	1, 16
	t <sub>7+13+</sub>	14			7, 13	14	8	1, 16
Carry In Inputs	t <sub>10–13+</sub>	14	7	9	10, 13	14	8	1, 16
	t <sub>13+10+</sub>	14	7	9	10, 13	14	8	1, 16
Hold Time Data Inputs	t <sub>13+12+</sub>	14		7, 9	12, 13	14	8	1, 16
	t <sub>13+12–</sub>	14		7, 9	12, 13	14	8	1, 16
Select Inputs	t <sub>13+9+</sub>	14			9, 13	14	8	1, 16
	t <sub>13+7+</sub>	14			7, 13	14	8	1, 16
Carry In Inputs	t <sub>13+10–</sub>	14	7	9	10, 13	14	8	1, 16
	t <sub>10+13+</sub>	14	7	9	10, 13	14	8	1, 16
Counting Frequency	f <sub>countup</sub>	14	7		13	14	8	1, 16
	f <sub>countdown</sub>	14	9		13	14	8	1, 16
Rise Time (20 to 80%)	t <sub>4+</sub>	4	7		13	4	8	1, 16
	t <sub>14+</sub>	14	7		13	14	8	1, 16
Fall Time (20 to 80%)	t <sub>4–</sub>	4	7		13	4	8	1, 16
	t <sub>14–</sub>	14	7		13	14	8	1, 16

1. Individually test each input; apply V<sub>ILmin</sub> to pin under test.

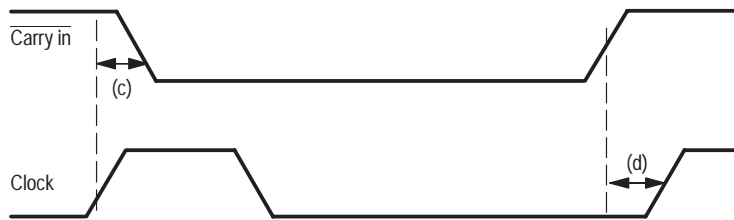
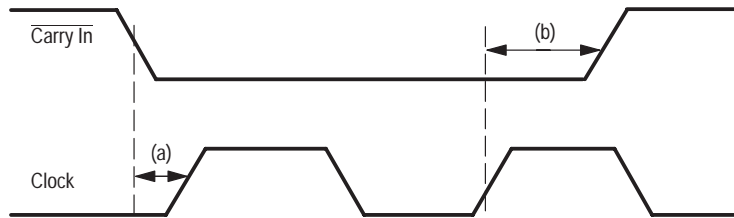
2. Measure output after clock pulse  V<sub>IH</sub> appears at clock input (Pin 13).

3. Before test set all Q outputs to a logic high.

Each MECL 10,000 series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained.

Outputs are terminated through a 50-ohm resistor to -2.0 volts. Test procedures are shown for only one gate. The other gates are tested in the same manner.

### SWITCHING TIME TEST CIRCUIT AND WAVEFORMS @ 25°C

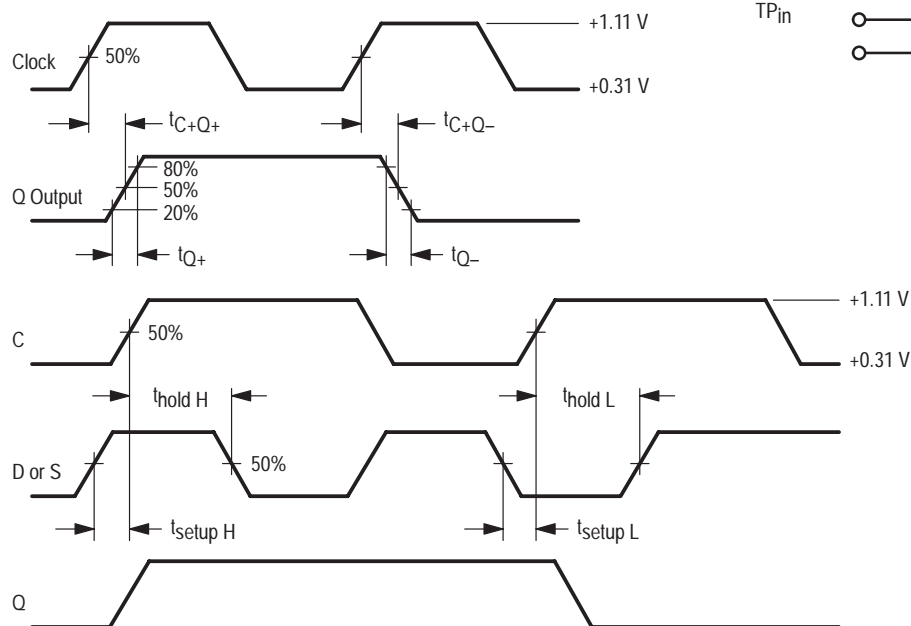


#### NOTE:

$t_{\text{setup}}$  is the minimum time before the positive transition of the clock pulse (C) that information must be present at the input D or S.

$t_{\text{hold}}$  is the minimum time after the positive transition of the clock pulse (C) that information must remain unchanged at the input D or S.

Input Pulse  
 $t_+ = t_- = 2.0 \pm 0.2 \text{ ns}$   
 (20 to 80%)



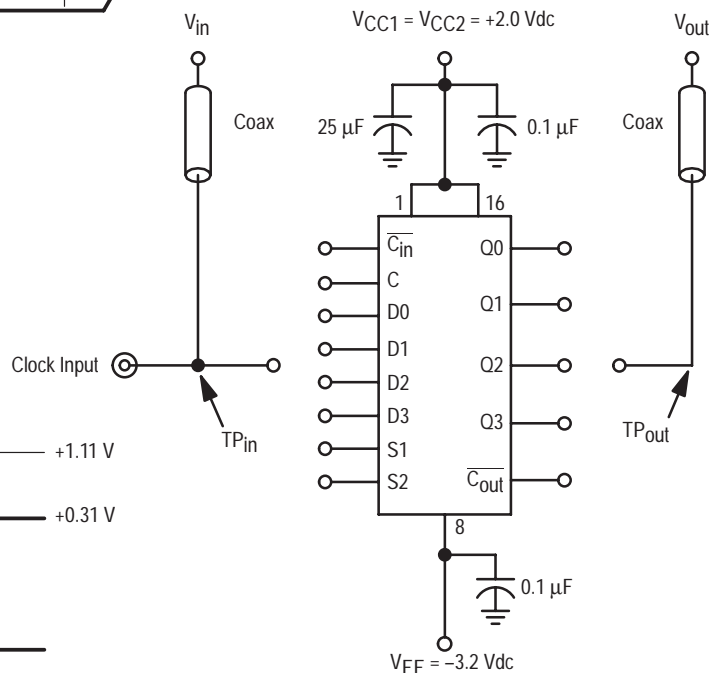
(a) is the minimum time to wait after the counter has been enabled to clock it.

(b) is the minimum time before the counter has been disabled that it may be clocked.

(c) is the minimum time before the counter is enabled that a clock pulse may be applied with no effect on the state of the counter.

(d) is the minimum time to wait after the counter is disabled that a clock pulse may be applied with no effect in the state of the counter.

(b) and (c) may be negative numbers.



50-ohm termination to ground located in each scope channel input.

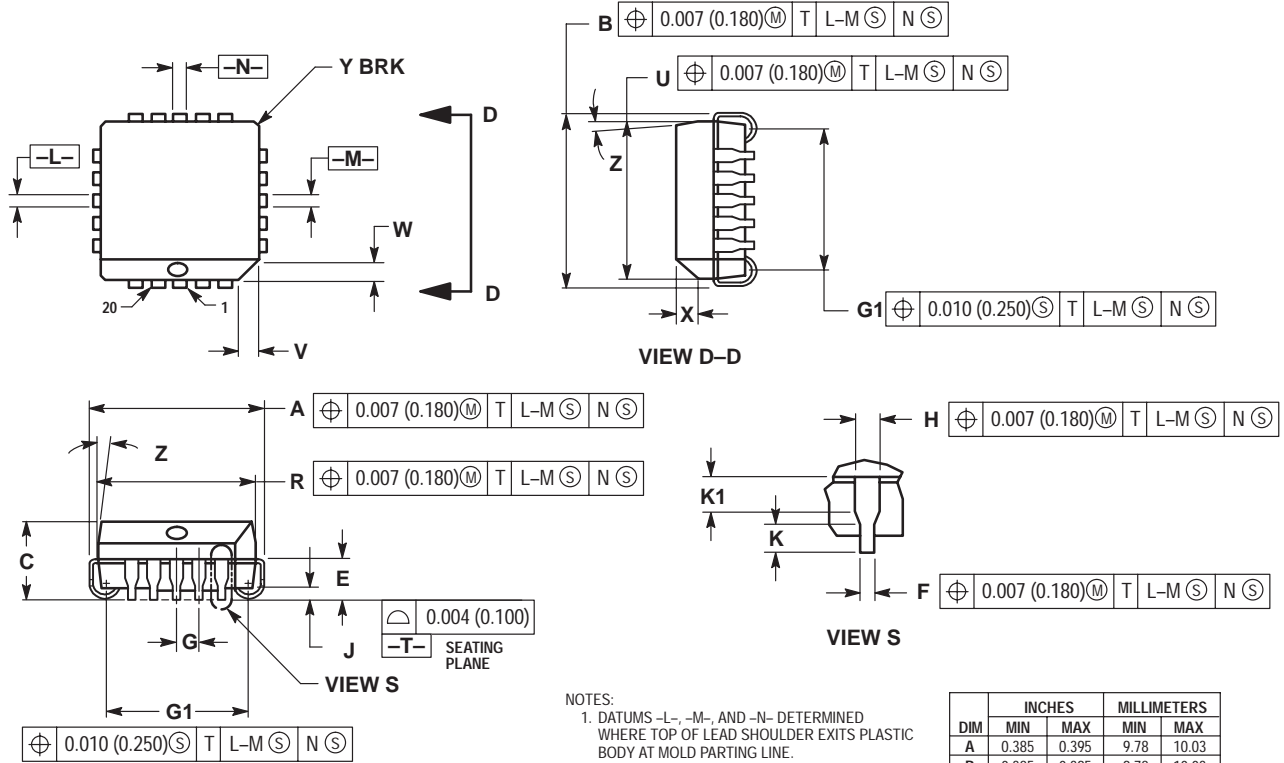
All input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from  $TP_{\text{in}}$  to input pin and  $TP_{\text{out}}$  to output pin.

Unused outputs are connected to a 50-ohm resistor to ground.

# MC10137

## PACKAGE DIMENSIONS

PLCC-20  
FN SUFFIX  
PLASTIC PLCC PACKAGE  
CASE 775-02  
ISSUE C



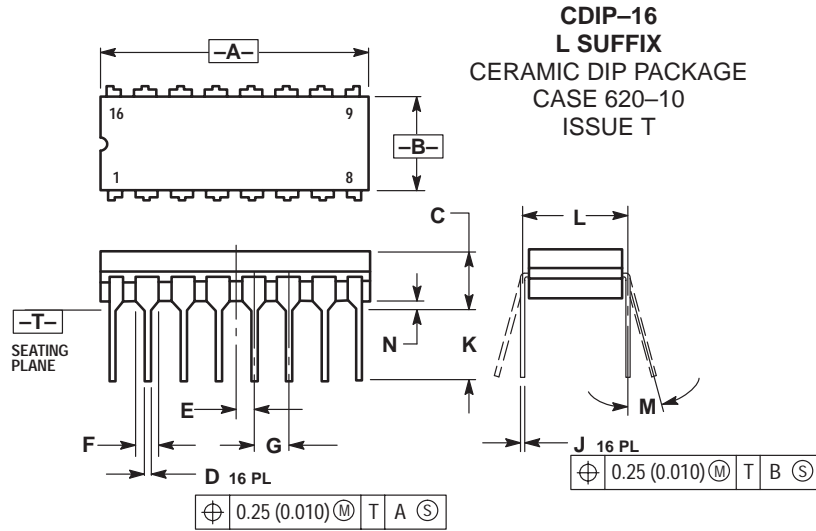
### NOTES:

- DATUMS -L-, -M-, AND -N- DETERMINED WHERE TOP OF LEAD SHOULDER EXITS PLASTIC BODY AT MOLD PARTING LINE.
- DIMENSION G1, TRUE POSITION TO BE MEASURED AT DATUM -T-, SEATING PLANE.
- DIMENSIONS R AND U DO NOT INCLUDE MOLD FLASH. ALLOWABLE MOLD FLASH IS 0.010 (0.250) PER SIDE.
- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: INCH.
- THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM BY UP TO 0.012 (0.300). DIMENSIONS R AND U ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY EXCLUSIVE OF MOLD FLASH, TIE BAR BURRS, GATE BURRS AND INTERLEAD FLASH, BUT INCLUDING ANY MISMATCH BETWEEN THE TOP AND BOTTOM OF THE PLASTIC BODY.
- DIMENSION H DOES NOT INCLUDE DAMBAR PROTRUSION OR INTRUSION. THE DAMBAR PROTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE GREATER THAN 0.037 (0.940). THE DAMBAR INTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE SMALLER THAN 0.025 (0.635).

DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.385	0.395	9.78	10.03
B	0.385	0.395	9.78	10.03
C	0.165	0.180	4.20	4.57
E	0.090	0.110	2.29	2.79
F	0.013	0.019	0.33	0.48
G	0.050 BSC		1.27 BSC	
H	0.026	0.032	0.66	0.81
J	0.020	---	0.51	---
K	0.025	---	0.64	---
R	0.350	0.356	8.89	9.04
U	0.350	0.356	8.89	9.04
V	0.042	0.048	1.07	1.21
W	0.042	0.048	1.07	1.21
X	0.042	0.056	1.07	1.42
Y	---	0.020	---	0.50
Z	2 °	10 °	2 °	10 °
G1	0.310	0.330	7.88	8.38
K1	0.040	---	1.02	---

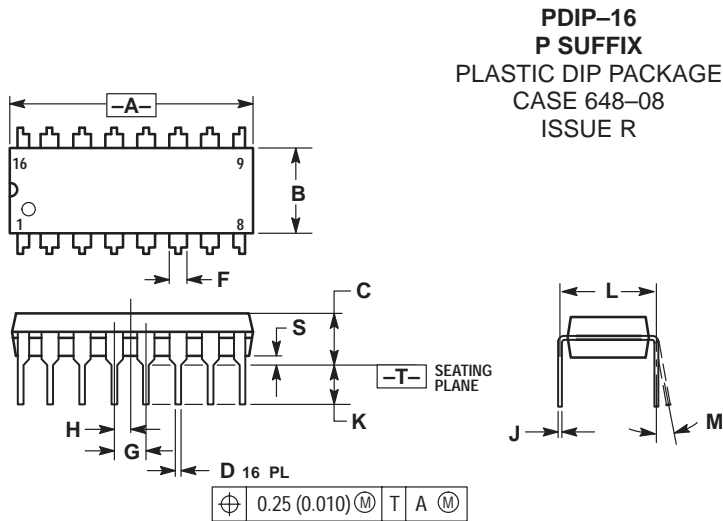
# MC10137

## PACKAGE DIMENSIONS




- NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: INCH.
  3. DIMENSION L TO CENTER OF LEAD WHEN FORMED PARALLEL.
  4. DIMENSION F MAY NARROW TO 0.76 (0.030) WHERE THE LEAD ENTERS THE CERAMIC BODY.

DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.750	0.785	19.05	19.93
B	0.240	0.295	6.10	7.49
C	---	0.200	---	5.08
D	0.015	0.020	0.39	0.50
E	0.050 BSC		1.27 BSC	
F	0.055	0.065	1.40	1.65
G	0.100 BSC		2.54 BSC	
H	0.008	0.015	0.21	0.38
K	0.125	0.170	3.18	4.31
L	0.300 BSC		7.62 BSC	
M	0°	15°	0°	15°
N	0.020	0.040	0.51	1.01



- NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: INCH.
  3. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL.
  4. DIMENSION B DOES NOT INCLUDE MOLD FLASH.
  5. ROUNDED CORNERS OPTIONAL.

DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.740	0.770	18.80	19.55
B	0.250	0.270	6.35	6.85
C	0.145	0.175	3.69	4.44
D	0.015	0.021	0.39	0.53
F	0.040	0.70	1.02	1.77
G	0.100 BSC		2.54 BSC	
H	0.050 BSC		1.27 BSC	
J	0.008	0.015	0.21	0.38
K	0.110	0.130	2.80	3.30
L	0.295	0.305	7.50	7.74
M	0°	10°	0°	10°
S	0.020	0.040	0.51	1.01

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